Power MOSFET N-Channel ChipFET™

4.9 Amps, 30 Volts

Features

- Low R_{DS(on)} for Higher Efficiency
- Miniature ChipFET Surface Mount Package

Applications

• Power Management in Portable and Battery-Powered Products; i.e., Cellular and Cordless Telephones and PCMCIA Cards

MAXIMUM RATINGS (T_A = 25°C unless otherwise noted)

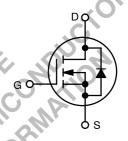
Rating	Symbol	5 secs	Steady State	Unit
Drain-Source Voltage	V _{DS}	3	V	
Gate-Source Voltage	V _{GS}	±	V	
Continuous Drain Current $(T_J = 150^{\circ}C)$ (Note 1.) $T_A = 25^{\circ}C$ $T_A = 85^{\circ}C$	I _D	±6.7 ±4.8	±4.9 ±3.5	A
Pulsed Drain Current	I _{DM}	±20		Α
Continuous Source Current (Diode Conduction) (Note 1.)	Is	2.1	1.1	А
Maximum Power Dissipation (Note 1.) T _A = 25°C T _A = 85°C	P _D	2.5 1.3	1.3 0.7	W
Operating Junction and Storage Temperature Range	T _J , T _{stg}	–55 to	+150	°C
1. Surface Mounted on 1" x 1" FR4 E	Board.	PRE		



ON Semiconductor™

http://onsemi.com

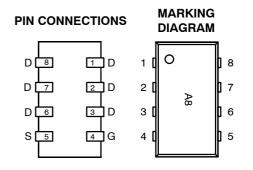
4.9 AMPS 30 VOLTS $R_{DS(on)} = 35 \text{ m}\Omega$



N-Channel MOSFET



ChipFET **CASE 1206A** STYLE 1



A8 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping
NTHS5402T1	ChipFET	3000/Tape & Reel

THERMAL CHARACTERISTICS

Characteristic	Symbol	Тур	Max	Unit
$\label{eq:maximum Junction-to-Ambient (Note 2.)} $t \leq 5 sec$$ Steady State$	R _{thJA}	40 80	50 95	°C/W
Maximum Junction-to-Foot (Drain) Steady State	R _{thJF}	15	20	°C/W

$\textbf{ELECTRICAL CHARACTERISTICS} \ (T_J = 25^{\circ}\text{C unless otherwise noted})$

Characteristic	Symbol	Test Condition	Min	Тур	Max	Unit
Static						
Gate Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0	-	-	V
Gate-Body Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	_	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 24 V, V _{GS} = 0 V	-	-	1.0	μΑ
		$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V},$ $T_{J} = 85^{\circ}\text{C}$	-	-	5.0	
On-State Drain Current (Note 3.)	I _{D(on)}	$V_{DS} \ge 5.0 \text{ V}, V_{GS} = 10 \text{ V}$	20	- / () -	Α
Drain-Source On-State Resistance (Note 3.)	r _{DS(on)}	V _{GS} = 10 V, I _D = 4.9 A	-	0.030	0.035	Ω
		$V_{GS} = 4.5 \text{ V}, I_D = 3.9 \text{ A}$	-	0.045	0.055	
Forward Transconductance (Note 3.)	9 _{fs}	V _{DS} = 10 V, I _D = 4.9 A	-1	15	_	S
Diode Forward Voltage (Note 3.)	V _{SD}	I _S = 1.1 A, V _{GS} = 0 V	.O,	0.8	1.2	V
Oynamic (Note 4.)		-0 ¹ / ₁	7 . "	P		•
Total Gate Charge	Q_g	02 (1)	Œ,	13	20	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V},$ $I_{D} = 4.9 \text{ A}$) -	1.3	-	
Gate-Drain Charge	Q_{gd}	16 90 21	_	3.1	-	
Turn-On Delay Time	t _{d(on)}	4, 0	-	10	15	ns
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_L = 15 \Omega$	-	10	15	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 1.0 \text{ A, } V_{\text{GEN}} = 10 \text{ V,}$ $R_{\text{G}} = 6 \Omega$	_	25	40	
Fall Time	t _f		_	10	15	
Source-Drain Reverse Recovery Time	St _{rr}	I _F = 1.1 A, di/dt = 100 A/μs	-	30	60	

- Source–Drain Reverse Recovery Time

 2. Surface Mounted on 1" x 1" FR4 Board.
 3. Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.
 4. Guaranteed by design, not subject to production testing.

TYPICAL CHARACTERISTICS

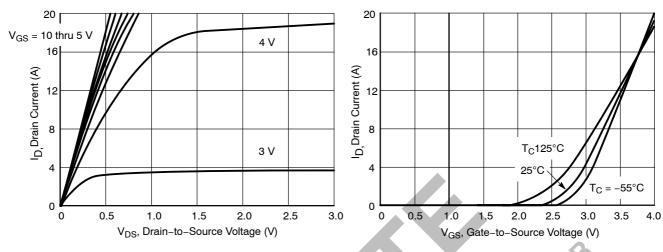


Figure 1. Output Characteristics

Figure 2. Transfer Characteristics

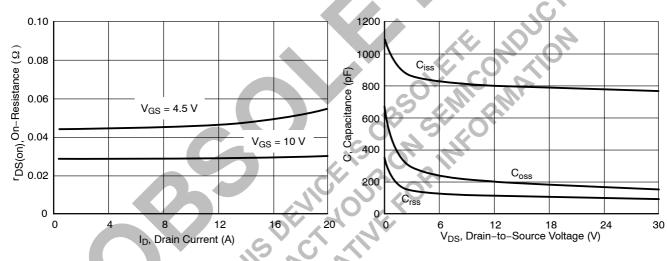


Figure 3. On-Resistance vs. Drain Current

Figure 4. Capacitance

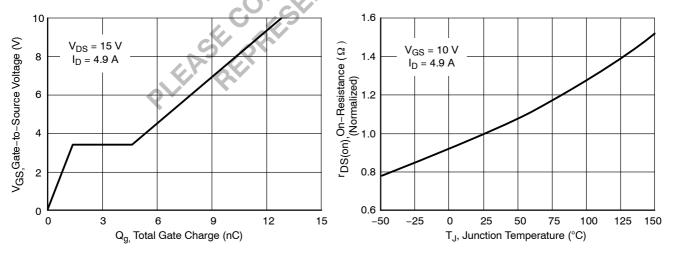
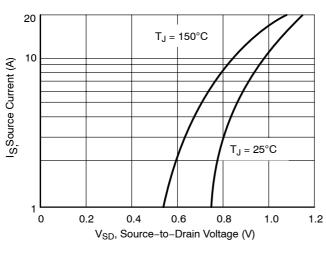


Figure 5. Gate Charge

Figure 6. On–Resistance vs. Junction Temperature

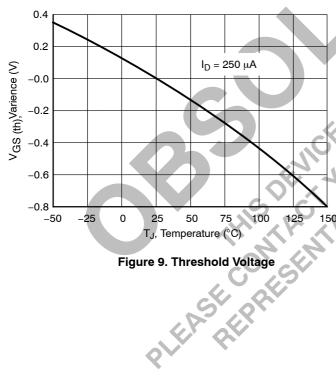
TYPICAL CHARACTERISTICS



0.10 $I_D = 4.9 A$ 0 0 10 V_{GS}, Gate-to-Source Voltage (V)

Figure 7. Source-Drain Diode Forward Voltage

Figure 8. On-Resistance vs. Gate-to-Source Voltage



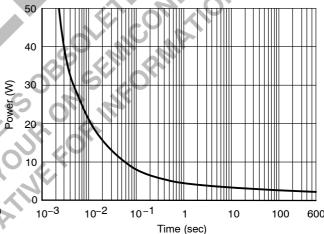


Figure 10. Single Pulse Power

TYPICAL CHARACTERISTICS

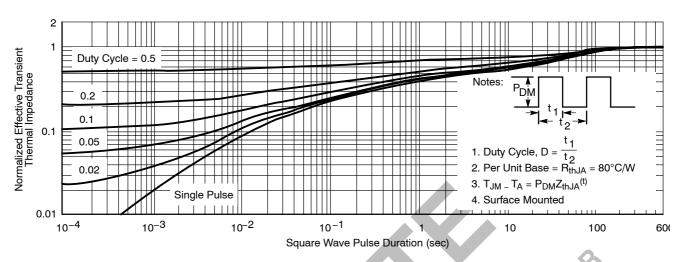
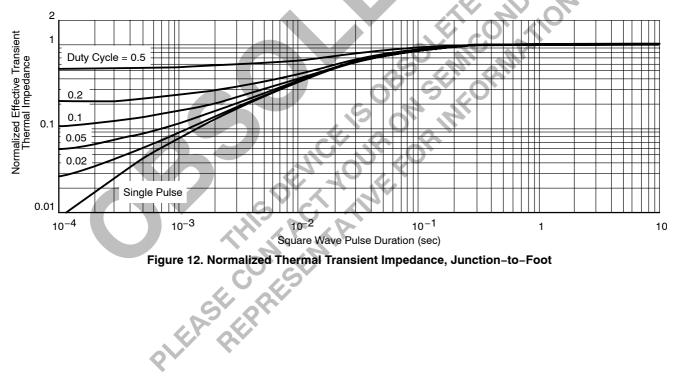
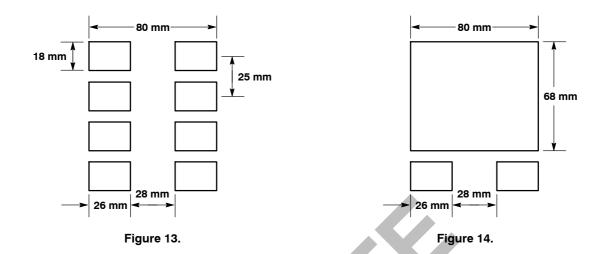


Figure 11. Normalized Thermal Transient Impedance, Junction-to-Ambient





BASIC PAD PATTERNS

The basic pad layout with dimensions is shown in Figure 13. This is sufficient for low power dissipation MOSFET applications, but power semiconductor performance requires a greater copper pad area, particularly for the drain leads.

The minimum recommended pad pattern shown in Figure 14 improves the thermal area of the drain connections (pins 1, 2, 3, 6, 7, 8) while remaining within the

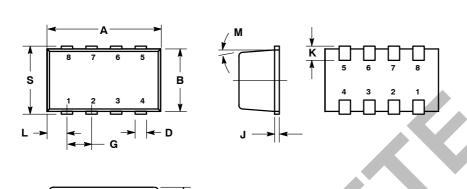
confines of the basic footprint. The drain copper area is 0.0054 sq. in. (or 3.51 sq. mm). This will assist the power and into

Ale) for the sin,

Ale area and/or the availl enhance the perform. dissipation path away from the device (through the copper leadframe) and into the board and exterior chassis (if applicable) for the single device. The addition of a further copper area and/or the addition of vias to other board layers will enhance the performance still further.

PACKAGE DIMENSIONS

ChipFET CASE 1206A-03 **ISSUE C**



NOTES:

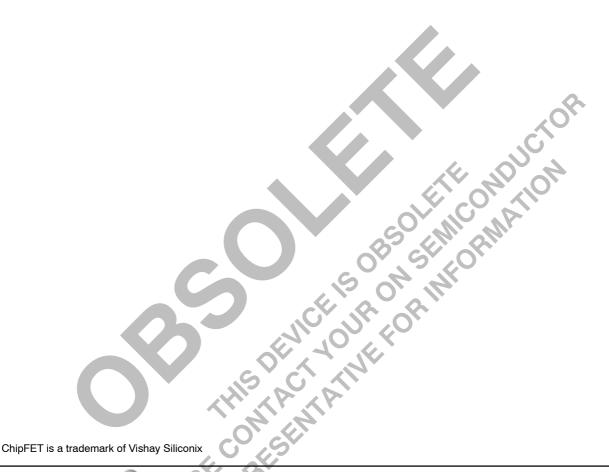
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: MILLIMETER.
 3. MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM
- PER SIDE.

 4. LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0 08 MM
- DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE
- BURRS. NO MOLD FLASH ALLOWED ON THE TOP AND 6.
- BOTTOM LEAD SURFACE. 1206A-01 AND 1206A-02 OBSOLETE. NEW STANDARD IS 1206A-03.

→			MILLIN	METERS	INC	HES
G		DIM	MIN	MAX	MIN	MAX
		A	2.95	3.10	0.116	0.122
		В	1.55	1.70	0.061	0.067
		С	1.00	1.10	0.039	0.043
		D	0.25	0.35	0.010	0.014
↑		G	0.6	BSC		5 BSC
C		J	0.10	0.20	0.004	0.008
		K	0.28	0.42 5 BSC	0.011	0.017 2 BSC
0 005 (0 000)		M	5.°	NOM		NOM
△ 0.05 (0.002)		S	1.80	2.00	0.072	0.080
			1.00	2.00	0.072	0.000
	() ()	STYLE	1:			
		PIN	1. DRAII	N		
			 DRAII DRAII 	N		
		T_{-}	4. GATE	N :		
		12	5. SOUP			
			6. DRAII	N		
	\mathcal{A}_{λ} \mathcal{O}_{λ} \mathcal{O}_{λ}		7. DRAII			
			8. DRAII	N		
	Je 711					
	0, 112					
	` ,()`					
. 19.19.						
. 0 //3						
V. AV						
O w						
0.05 (0.002)						

- PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. GATE

 - 5. SOURCE 6. DRAIN 7. DRAIN 8. DRAIN



ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer.

PUBLICATION ORDERING INFORMATION

Literature Fulfillment:

Literature Distribution Center for ON Semiconductor P.O. Box 5163, Denver, Colorado 80217 USA

Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada **Fax**: 303-675-2176 or 800-344-3867 Toll Free USA/Canada

Email: ONlit@hibbertco.com

N. American Technical Support: 800-282-9855 Toll Free USA/Canada

JAPAN: ON Semiconductor, Japan Customer Focus Center 4–32–1 Nishi–Gotanda, Shinagawa–ku, Tokyo, Japan 141–0031

Phone: 81–3–5740–2700 **Email**: r14525@onsemi.com

ON Semiconductor Website: http://onsemi.com

For additional information, please contact your local

Sales Representative.